

## **Four Probe System**

Used for resistivity, sheet resistance and thickness (if resistivity is known) calculation for the metal films.

- 2", 4", and 8" wafers can be used in this system.
- It can measure the sheet resistance from 0.001 Ohm/Sq to 800 KOhm/Sq.
- We can use bare Si wafer, oxide wafers, and metals deposited wafers.
- The tip used in the 4 Probe system is having tip radius of 300um with a spacing of 1mm.